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<u>L21</u> 711/103.CCLS.	738	<u>L21</u>
DB=TDBD; PLUR=YES; OP=ADJ		
(modif\$ or updat\$ or chang\$ or alter\$) near4 program\$ and (redirect\$ OR		
<u>L20</u> TRANSFER\$ OR TRANSMIT\$) and address and (mark\$ or tag\$) near5	0	<u>L20</u>
address\$ AND REPLAC\$ NEAR4 (INVALID\$ OR DISABL\$)		
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<u>L18</u> TRANSFER\$ OR TRANSMIT\$) and address and (mark\$ or tag\$) near5	0	<u>L18</u>
address\$ AND REPLAC\$ NEAR4 (INVALID\$ OR DISABL\$)		
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<u>L17</u>	(modif\$ or updat\$ or chang\$ or alter\$) near4 program\$ and (redirect\$ OR TRANSFER\$ OR TRANSMIT\$) and address and (mark\$ or tag\$) near5 address\$ AND REPLAC\$ NEAR4 (INVALID\$ OR DISABL\$)	0	<u>L17</u>
	<i>DB=PGPB; PLUR=YES; OP=ADJ</i>		
<u>L16</u>	(modif\$ or updat\$ or chang\$ or alter\$) near4 program\$ and (redirect\$ OR TRANSFER\$ OR TRANSMIT\$) and address and (mark\$ or tag\$) near5 address\$ AND REPLAC\$ NEAR4 (INVALID\$ OR DISABL\$)	13	<u>L16</u>
<u>L15</u>	L8 AND REPLAC\$ NEAR4 (INVALID\$ OR DISABL\$)	0	<u>L15</u>
	<i>DB=USPT; PLUR=YES; OP=ADJ</i>		
<u>L14</u>	L8 AND REPLAC\$ NEAR4 (INVALID\$ OR DISABL\$)	36	<u>L14</u>
<u>L13</u>	712/233.CCLS.	241	<u>L13</u>
<u>L12</u>	711/133,134.CCLS.	566	<u>L12</u>
<u>L11</u>	711/144,146,3.CCLS.	1372	<u>L11</u>
<u>L10</u>	712/209,210.CCLS.	520	<u>L10</u>
<u>L9</u>	L8 AND L1	5	<u>L9</u>
<u>L8</u>	(modif\$ or updat\$ or chang\$ or alter\$) near4 program\$ and (redirect\$ OR TRANSFER\$ OR TRANSMIT\$) and address and (mark\$ or tag\$) near5 address\$	1644	<u>L8</u>
<u>L7</u>	L6 AND L1	1	<u>L7</u>
<u>L6</u>	(modif\$ or updat\$ or chang\$ or alter\$) near4 program\$ and redirect\$ and address and (mark\$ or tag\$) near5 address\$	180	<u>L6</u>
<u>L5</u>	L2 and L1	0	<u>L5</u>
<u>L4</u>	L3 and L1	0	<u>L4</u>
<u>L3</u>	L2 and (invalid\$ or disabl\$)	70	<u>L3</u>
<u>L2</u>	(modif\$ or updat\$ or chang\$ or alter\$) near4 program\$ and redirect\$ and address and (mark\$ near5 address\$)	82	<u>L2</u>
<u>L1</u>	717/168,129,127.ccls.	504	<u>L1</u>

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1 [Continuous program optimization: A case study](#)

Thomas Kistler, Michael Franz

July 2003 **ACM Transactions on Programming Languages and Systems (TOPLAS)**,

Volume 25 Issue 4

Full text available: pdf(877.67 KB) Additional Information: [full citation](#), [abstract](#), [references](#), [index terms](#)

Much of the software in everyday operation is not making optimal use of the hardware on which it actually runs. Among the reasons for this discrepancy are hardware/software mismatches, modularization overheads introduced by software engineering considerations, and the inability of systems to adapt to users' behaviors. A solution to these problems is to delay code generation until load time. This is the earliest point at which a piece of software can be fine-tuned to the actual capabilities of the ...

Keywords: Dynamic code generation, continuous program optimization, dynamic reoptimization

2 [Enabling trusted software integrity](#)

Darko Kirovski, Milenko Drinić, Miodrag Potkonjak

October 2002 **Proceedings of the 10th international conference on architectural support for programming languages and operating systems**, Volume 37 , 30 ,

36 Issue 10 , 5 , 5

Full text available: pdf(1.39 MB) Additional Information: [full citation](#), [abstract](#), [references](#)

Preventing execution of unauthorized software on a given computer plays a pivotal role in system security. The key problem is that although a program at the beginning of its execution can be verified as authentic, while running, its execution flow can be redirected to externally injected malicious code using, for example, a buffer overflow exploit. Existing techniques address this problem by trying to detect the intrusion at run-time or by formally verifying that the software is not prone to a p ...

3 [Simultaneous subordinate microthreading \(SSMT\)](#)

Robert S. Chappell, Jared Stark, Sangwook P. Kim, Steven K. Reinhardt, Yale N. Patt

May 1999 **ACM SIGARCH Computer Architecture News , Proceedings of the 26th annual international symposium on Computer architecture**, Volume 27 Issue 2Full text available: pdf(129.54 KB) Additional Information: [full citation](#), [abstract](#), [references](#), [citations](#), [index terms](#)
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